

<b>FORM PTO-149</b> US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  If AFTER the later date of the first Office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee  <b>LIST OF ART CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>	Atty. Docket No. <b>78515DMW</b>	Serial No. <b>09/406 882</b>
	Applicant: <b>Peter D. Burns</b>	
Filing Date <b>28 September 1999</b>		Group <b>2612</b>

U.S. PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>[Signature]</i>	4,849,914	7/18/89	Gerard G. R. Medioni et al.	382	112	9/22/87
<i>[Signature]</i>	5,325,190	6/28/94	Tatsuo Nagasaki et al.	348	270	10/1/92
<i>[Signature]</i>	5,475,428	12/12/95	Wayne W. Hintz et al.	348	263	9/9/93

FOREIGN PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES   NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
"Fundamentals of Digital Image Processing" by Anil K. Jain. Prentice-Hall International, Inc., pp. 244-263.	
"Design of Constrained Digital Filters for Restoration and Enhancement: by Stephen K. Park and Stephen E. Reichenbach. The Society for Imaging Science and Technology, May 20-25, 1990. pp. 242-244	
"The design of 2-D approximately linear phase filters using a direct approach" by Stuart Lawson and Martin Anderson. <u>Signal Processing</u> 57, pp. 205-221, 1997.	
Optics, 2 <sup>nd</sup> ed., Addison-Wesley Publishing Co.: Reading, Massachusetts, pp. 232-233, 1987.	
"Electronic Still Picture Camera Spatial Frequency Response Measurement" by Timothy A. Fischer and Jack Holm. <u>Proc. of IS&amp;T 47<sup>th</sup> Annual Conf., ICPS 1994</u> , vol 2. pp. 626-630 (1994)	
"Benchmarking of the ISO 12233 Slanted-edge Spatial Frequency Response Plug-in" by Don Williams. <u>Proc. of IS&amp;T Annual Conf.</u> , (1998).	

EXAMINER <i>[Signature]</i>	DATE CONSIDERED <b>6/17/03</b>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	